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## Communications

## High-Performance n-Type Organic Thin-Film Transistors Based on Solution-Processable Perfluoroalkyl-Substituted C<sub>60</sub> Derivatives

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In recent years, organic thin-film transistors (TFTs) based on solution-processable organic semiconductors have been attracting interest concerning both fundamental research and practical application for low-cost, large-area, and flexible devices.<sup>1-4</sup> Development of high-performance p-type and n-type materials is crucial for realizing not only p—n junction devices such as organic light-emitting diodes and photovoltaic cells but also organic complementary metal-oxidesemiconductor (CMOS). However, variation of solutionprocessable n-type materials with high carrier mobility and stability is limited compared with that of p-type materials. Therefore, development of high performance n-type materials is important for further progress of organic electronic devices.<sup>5–18</sup>

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In our previous study, we developed long-chain alkylsubstituted  $C_{60}$  derivatives. C60-fused *N*-methylpyrrolidine*meta*-dodecyl phenyl, C60MC12 (**2**), forms highly ordered crystalline film by solution process and exhibits high electron mobility of  $0.06-0.09 \text{ cm}^2/\text{Vs}$ ,<sup>17,18</sup> which is superior compared with a well-known solution-processable n-type material, [6,6]-phenyl C61-butyric acid methyl ester, PCBM (**1**), that tends to take an amorphous-like structure. However, these compounds do not exhibit TFT performance in air, because O<sub>2</sub> and H<sub>2</sub>O diffuse into channel region and act as trap spices of electron transport. To realize both high electron mobility and air stability, we have focused on long-chain perfluoroalkyl-substituted C<sub>60</sub> derivatives. Since perfluoroalkyl chains are known to act as an efficient gas barrier, TFTs

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Figure 1. XRD patterns of spin-coated (a) C60MC8F17, (b) C60PC8F17, and (c) C60PC12F25 films.



Figure 2. (a) Output and (b) transfer characteristics of a TFT based on C60PC12F25.

based on these compounds are expected to exhibit *n*-channel characteristics in air.

In this communication, we report new solution-processable perfluoroalkyl-substituted  $C_{60}$  derivatives **3–5**, which exhibit high electron mobility and air stability.



New  $C_{60}$  derivatives 3–5 were synthesized according to Scheme S1 (see the Supporting Information). The electronic state of the  $C_{60}$  portion in **1–5** is almost the same, because each of the functional groups in 1-5 adds to a 6:6 ring juncture of C<sub>60</sub>. Each film of **3–5** was fabricated on HMDStreated SiO<sub>2</sub>/p<sup>+</sup>-Si by spin coating from a chloroform solution under ambient condition. The microstructure of spin-coated films was investigated by X-ray diffraction (XRD) measurement (Figure 1). The spin-coated films of perfluoroalkyl substituted C<sub>60</sub> via the para position of phenyl group (C60PC8F17, C60PC12F25) exhibited high crystallinity compared to that via the meta position of phenyl group (C60MC8F17). The XRD patterns of C60PC8F17 and C60PC12F25 films showed 00L reflections up to higherorder, indicating formation of ordered structure. The spacings of the (001) planes of C60PC8F17 and C60PC12F25 films are calculated to be 2.57 and 2.70 nm, respectively. These results indicate that the film crystallinity strongly depends on both fluoroalkyl-chain orientation and length.

Figure 2 shows output and transfer characteristics of the TFT based on C60PC12F25 in a vacuum at room temperature. The device showed excellent n-channel characteristics. The field-effect electron mobility ( $\mu_e$ ) in saturation regime is calculated to be 0.25 cm<sup>2</sup>/Vs. The average  $\mu_e$  of four devices is 0.23 cm<sup>2</sup>/Vs, which is one of the highest value



Figure 3. Temperature dependence of the field-effect mobility extracted from the characteristics of C60PC12F25- and PCBM-TFT in the saturation regime ( $V_D = 50$  V).

Table 1. Field-Effect Electron Mobilities $(\mu)$ , Threshold Voltage
$(V_{\rm T})$ , and Current On/Off Ratios $(I_{\rm on}/I_{\rm off})$ for TFTs Measured in a
Vacuum and Air

	vacuum			air <sup>a</sup>		
compound	$\mu$ (cm <sup>2</sup> /Vs)	$V_{\rm T}~({\rm V})$	$I_{\rm on}/I_{\rm off}$	$\mu$ (cm <sup>2</sup> /Vs)	$V_{\rm T}({\rm V})$	$I_{\rm on}/I_{\rm off}$
C60MC8F17 C60PC8F17 C60PC12F25 PCBM C60MC12	0.024 0.067 0.25 0.025 0.090	21 22 28 33 24	$\begin{array}{c} 5\times 10^{4} \\ 2\times 10^{5} \\ 4\times 10^{5} \\ 2\times 10^{4} \\ 2\times 10^{5} \end{array}$	$4 \times 10^{-4}$ 0.008 0.078 NA <sup>b</sup> NA <sup>b</sup>	55 46 51	$\begin{array}{c} 1\times10^2\\ 7\times10^3\\ 4\times10^4\end{array}$

<sup>a</sup> After exposure to air for 5 h. <sup>b</sup> Not active.

among those of previously reported solution-processed n-type organic TFTs.<sup>10-14</sup> C60MC8F17- and C60PC8F17-TFTs also exhibited typical n-channel characteristics (Figures S2 and S3 in the Supporting Information) and high mobilities of 0.024 and 0.067 cm<sup>2</sup>/(V s), respectively.

Figure 3 shows temperature dependence of field-effect electron mobility between 100 and 300 K in a vacuum. From the result of XRD measurement, the microstructure of the PCBM film is amorphous-like, whereas that of the C60PC12F25 film is crystalline. The mobilities of C60PC12F25- and PCBM-TFT decreased with decreasing temperature. The dependence of the mobility of the C60PC12F25-TFT is more moderate than that of the PCBM-TFT. The activation energy (*E*<sub>a</sub>) of the C60PC12F25-TFT given by  $\mu \propto \exp(-E_a/kT)$  is 27 meV in the range 225-275K, which is small compared with that of the PCBM-TFT (71 meV). Trap density  $(N_{trap})$ can be estimated by  $N_{\text{trap}} = C_i(V_T - V_{TO})/e$ , where  $C_i$  is the capacitance per unit area of gate dielectric,  $V_{\rm T}$  is the threshold voltage,  $V_{\rm TO}$  is the turn-on voltage, e is the elementary charge.<sup>24,25</sup> Estimated trap density of C60PC12F25 film (1.2  $\times 10^{12}$  cm<sup>-2</sup>) was comparable with that of PCBM film (1.3  $\times 10^{12}$  cm<sup>-2</sup>). However, the C60PC12F25 film shows higher  $\mu_{\rm e}$  and smaller  $E_{\rm a}$ . The results indicate that C60PC12F25 molecules in the crystalline grain form stronger  $\pi - \pi$ interaction compared with PCBM molecules in the amorphouslike domain because of the improvement in structural order. The results also indicate that electron traps between grain boundaries in the C60PC12F25 film are very shallow.

After exposure to air, TFTs based on 3-5 exhibited *n*-channel characteristics (Figures S6–S8 in the Supporting Information), whereas the TFTs employing C<sub>60</sub> derivatives with a hydrocarbon chain (PCBM and C60MC12) did not operate (Figure S9). TFT performance of each device is summarized in Table 1. Electrochemical properties of the C<sub>60</sub> derivatives were investigated by cyclic voltammetry (see the Supporting Information). The lowest unoccupied molecular orbital (LUMO) levels of the C<sub>60</sub> derivatives were calculated by using the onset of the reduction peak

 
 Table 2. Electrochemical Properties<sup>a</sup> and the Corresponding LUMO Energies

compd	$E^{1}_{red}$ (V)	Ered/onset (V)	LUMO (eV)
C60MC8F17 (3)	-0.61	-0.55	-3.63
C60PC8F17 (4)	-0.61	-0.55	-3.63
C60PC12F25 (5)	-0.61	-0.55	-3.63
PCBM (1)	-0.59	-0.52	-3.66
C60MC12 (2)	-0.63	-0.57	-3.61

<sup>a</sup> V vs Ag/AgCl, 0.05 M n-Bu<sub>4</sub>NPF<sub>6</sub> in ODCB.



Figure 4. Time dependence of drain current of TFTs after exposure to air ( $V_D = 50 \text{ V}$ ,  $V_G = 70 \text{ V}$ ).

 $(E_{\text{red/onset}})$  according to the empirical equation,<sup>8,11,20</sup> LUMO (eV) =  $-[E_{\text{red/onset}} - E_{1/2} \text{ (Fc/Fc}^+) + 4.8]$ . The LUMO energies of the five different materials are almost the same with one another as shown in Table 2 (-3.61 eV to approximately -3.66 eV).

There are several reports concerning the correlation between electron affinity of n-type materials and air stability.<sup>19–21</sup> Anthopoulos et al. reported that n-type materials with electron affinity <4 eV are unstable in air.<sup>19</sup> However, in spite of the perfluoroalkyl-substituted C<sub>60</sub> derivatives (**3**–**5**) with low electron affinity (3.63 eV), the TFTs showed *n*-channel characteristics in air. These results indicate that air stability of C<sub>60</sub>-based TFTs is attributed to introduction of a long-chain perfluoroalkyl group to C<sub>60</sub>. Because fluorocarbon chains tend to be packed densely, diffusion of O<sub>2</sub> and H<sub>2</sub>O into the channel region can be prevented, leading to improvement of air stability.<sup>5,21–23</sup>

Figure 4 shows the time dependence of drain current of the TFTs after exposure to air. Difference in air stability of the

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Figure 5. An optical microscopic image of a C60PC12F25 film. Two gold lines are source and drain electrodes.

TFTs was observed. The air stability is in the order of C60PC12F25 > C60PC8F17 > C60MC8F17, which agrees with the order of the film crystallinity. In particular, C60PC12F25-TFT exhibits high air stability and good *n*-channel characteristics even after exposure to air for 144 h. From the results of XRD and TFT measurement, it was found that fabrication of ordered crystalline film is important for realizing both high electron mobility and air stability of TFTs based on perfluoroalkyl-substituted C<sub>60</sub> derivatives.

However, in the case of perfluoroalkyl-substituted  $C_{60}$  derivatives, a quick drop of the drain current was observed before reaching the steady state (Figure 4), which leads to  $V_T$  shifts to positive voltage and decrease of mobility in air (Table 1). These results can be explained by diffusion of  $O_2$  and  $H_2O$  into the channel from amorphous regions or grain boundaries. An optical microscopic image of a C60PC12F25 film shows an inhomogenious microstructure that has large crystalline domains from 10 to 30  $\mu$ m dispersed in the film (Figure 5). By optimizing thin-film fabrication condition, further improvement of crystallinity and air-stability is expected.

In summary, we have demonstrated n-type organic TFTs based on solution-processable perfluoroalkyl-substituted  $C_{60}$  derivatives. C60PC12F25-TFTs exhibit high electron mobility of 0.25 cm<sup>2</sup>/(V s) and can operate in air. The mobility is one of the highest value among those of previously reported solution-processed n-type organic TFTs. We found that introduction of a long-chain perfluoroalkyl group to  $C_{60}$  is effective for fabrication of stable and high performance n-type organic TFTs.

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**Supporting Information Available:** Experimental procedures and additional data (PDF). This material is available free of charge via the Internet at http://pubs.acs.org.

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